

**Search Notes**

Application/Control No.

10/593,434

Examiner

Hai H. Huynh

Applicant(s)/Patent under  
Reexamination

LUDWIG ET AL.

Art Unit

3747

**SEARCHED**

Class	Subclass	Date	Examiner
123	143B	12/17/2007	HHH
123	143C	12/17/2007	HHH
123	145R	12/17/2007	HHH
123	145A	12/17/2007	HHH
73	116	12/17/2007	HHH
73	118.1	12/17/2007	HHH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	12/17/2007	HHH